JAN 1 7 2006 W

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

ADEMA:	
Application Serial No	10/632,273
Filing Date	July 31, 2003
Inventor	Warren M. Farnworth et al.
Assignee	
Group Art Unit	
Examiner	
Attorney's Docket No	Ml22-2379
Title: Method and Apparatus for Testing Semiconductor	
Method of Forming Apparatus for Testing Semicondo	

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patent listed on the attached Form PTO-1449. No admission is made regarding whether the submitted reference is prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 1-16-06

D. Brent Kenady

Reg. No. 40,045 Customer No. 021567

ST OF ART CITED BY APPLICANT (Use several sheets if necessary) JAN 1 7 2006

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MI22-2379

SERIAL NO. 10/632,273

APPLICANT

Warren M. Farnworth

FILING DATE July 31, 2003

GROUP 2829

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	ocument Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,201,992	4/93	Marcus, et al.	156	643		
-	AB							
	AC							
	AD						-	
	AE							
	AF							
	. AG							
	AH	<u></u>						
	Al							_
	AJ							
	AK							
	AL							
 -	L		FOI	REIGN PATENT DOCUMENTS				
		Document	Date Country		Class	Subclass	Translation	
	AM	Number		·			Yes	No
	AN							
	AO							
	AP							
	AQ				·			
		OTHER F	REFERENCE	6 (including Author, Title, Date, Pertine	ent Pages, Etc.)			
-	AR							
	AS							

*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.